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	er · Mi			EPO; JPO;	
ĺ				DERWENT;	*
*	· <u> </u>		039484.ap.	IBM_TDB	
	表	-	033404.ap.	USPAT;	2003/09/07 12:04
				US-PGPUB;	
[*				EPO; JPO; DERWENT;	
	•			IBM TDB	•
	-	28	method near4 circuit adj simulation.clm.	USPAT;	2003/09/07 12:08
				US-PGPUB;	2003/03/07 12:08
	***			EPO; JPO;	
.		-		DERWENT;	1
	* +5 *			IBM TDB	
		,	apparatus near6 computer adj simulation	USPAT;	2003/09/07 12:09
			near6 circuit.clm.	US-PGPUB;	
, ,				EPO; JPO;	
	·			DERWENT;	
				IBM_TDB	
		162	computer adj system near6 simulation.clm.	USPAT;	2003/09/07 12:10
,				US-PGPUB;	
		•		EPO; JPO;	
,		•		DERWENT;	
		8	(IIS-20030154064 6 am IIG 00000154055 a	IBM_TDB	
			(US-20030154064-\$ or US-20030154065-\$ or	US-PGPUB	2003/09/07 12:42
	184. ओ ऑ क		US-20030154447-\$ or US-20030154453-\$ or US-20030154454-\$ or US-20030163277-\$ or		
	AT, W. A.		US-20030154454-\$ or US-20030163277-\$ or US-20030163510-\$ or US-20030164239-\$).did.		
- [- ***	Ō	simulating.clm and apparatus.clm. and	i CDAM	0000/00/05
			design.clm.	USPAT;	2003/09/07 12:43
or "A		840	simulating near6 circuit.clm.	US-PGPUB USPAT;	2002/00/07 10
,	- printing **	, , ,		US-PGPUB	2003/09/07 12:44
	-	7	(US-20030154453-\$ or US-20030154454-\$ or	US-PGPUB	2004/05/19 11:21
			US-20030163277-\$ or US-20030163510-\$ or	00 10101	
			US-20030154447-\$ or US-20030154065-\$ or		
,			US-20030154064-\$).did.	· :	
		1136	((703/13) or (703/14)).CCLS.	ÚSPAT;	2004/05/19 13:54
				US-PGPUB	, 11, 12 20,04
'	-	42	(((703/13) or (703/14)).CCLS.) and method	USPAT;	2004/05/19 14:16
	* E.		near6 capacitance	US-PGPUB;	0
				EPO; JPO;	
. l	. ,			DERWENT;	· · · · · · · · · · · · · · · · · · ·
₩			(((1703/13) == 1703/145) ====================================	IBM_TDB	
·		. 0	(((703/13) or (703/14)).CCLS.) and method	USPAT;	2004/05/19 14:21
.			near6 capacitance and simulat\$3 near6	US-PGPUB;	
•]	· · · · · · · · · · · · · · · · · · ·		design adj structure	EPO; JPO;	
I		·		DERWENT;	
-	<u>.</u>	ńΙ	method near6 capacitance near6 simulat\$3	IBM TDB	. 2004/05/10 10 10
	18		and simul\$3 near6 design adj structure and	USPAT; US-PGPUB;	2004/05/19 15:16
	· .		parasitic adj capacitance	EPO; JPO;	
		1		DERWENT;	
				IBM_TDB	
=		0	method near6 capacitance near6 simulat\$3	USPAT;	2004/05/19 15:16
		·	and simul\$3 near6 design adj structure	US-PGPUB;	=004/00/ID ID:ID
				EPO; JPO;	•
	ľ			DERWENT;	
	·			IBM TDB	٠.
-	·	1814	circuit near3 simulat\$3.clm.	USPAT;	2004/05/19 15:16
				US-PGPUB;	
	,			EPO; JPO;	
	·			DERWENT;	
		65		IBM_TDB	•
-		95	circuit near3 simulat\$3.clm. and method	USPAT;	2004/05/19 15:35
		1	near6 (capacitance capacitor)	US-PGPUB;	
1.				EPO; JPO;	
	******	Í		DERWENT;	1
			•	IBM TDB	· .

Page 1

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	\$ \$	365 5			·		•
			- [34	circuit near3 simulat\$3.clm. and method	USPAT;	1 2004 /05 /10 17 06
	ण विकासिक		ļ. ļ:		near6 (capacitance capacitor) and design	US-PGPUB;	2004/05/19 17:26
- 					near6 simulat\$3	EPO; JPO;	
į.	12 14	*	· .			DERWENT;	
					**	IBM TDB	
٠,	<u> </u>			15	gallia.in. near6 james.in.	USPAT;	2004/05/10 17 00
• •	14	-25			James III.	US-PGPUB;	2004/05/19 17:29
.						EPO; JPO;	
			· [,		DERWENT;	·
- 1	•		·	, .		IBM TDB	
	- `			. 5	gallia.in. near6 james.in. and design\$3	USPAT;	2004/05/10 17 21
ĺ			·		and capacitance	US-PGPUB;	2004/05/19 17:31
						EPO; JPO;	· .
				•		DERWENT;	
		•	.			IBM TDB	1
				19	(design\$3 determin\$3) near3 capacitance	USPAT;	2004/05/19 17:33
· [.	•.•	near20 (circuit near2	UŠ-PGPÙB;	2004/03/19 17.33
.			1.		simulat\$3).ti,ab,clm.	EPO; JPO;	
İ				•		DERWENT;	
			1.			IBM TDB	
	· <u>-</u>	±		7	(design\$3 determin\$3) near3 capacitance	USPAT;	2004/05/20 10:38
	_\$·			. •	near20 (circuit near2	US-PGPUB;	-101,00,20 10.30
		•			simulat\$3).ti,ab,clm. and	EPO; JPO;	
ľ			1		parasitic.ti,ab,clm.	DERWENT;	
						IBM TDB	1
	- &	•		1137	((703/13) or (703/14)).CCLS.	USPAT;	2004/05/20 10:38
,			1			US-PGPUB;	
ن دائف	,		1.			EPO; JPO;	
	•		e c	•		DERWENT;	
			. •	50		IBM TDB	
	.—	. :	: .	58	(((703/13) or (703/14)) .CCLS.) and circuit	USPAT;	2004/05/20 10:51
					adj simulati\$2 and design and capacitance	US-PGPUB;	
,		**. *.	11.	, . *	and parasitic	EPO; JPO;	
	17	٠. ٠		3 4		DERWENT;	
					1117021121 - 150211111 - 55-	IBM_TDB	
	_	* *		.01	(((703/13) or (703/14)).CCLS.) and circuit	USPAT;	2004/05/20 10:52
1					adj simulati\$2 and design adj structure	US-PGPUB;	
	· .	· · ·		.,	and test adj structure and capacitance	EPO; JPO;	
1	理金 /					DERWENT;	
	.	•		0	(((703/13) or (703/14)).CCLS.) and circuit	IBM TDB	
				٠,	adj simulati\$2 and design adj structure	USPAT;	2004/05/20 10:52
1		*			and test adj structure	US-PGPUB;	
].	,				and sobe day beructure	EPO; JPO;	
^		٠				DERWENT; IBM TDB	
. -	.	•		158	(((703/13) or (703/14)).CCLS.) and circuit	USPAT;	2004/05/20 10 50
]		adj simulati\$2 and design and test	US-PGPUB;	2004/05/20 10:52
		.*				EPO; JPO;	
			11.			DERWENT;	
			0			IBM TDB	
-	.	. •		- 8	(((703/13) or (703/14)).CCLS.) and circuit	USPAT;	2004/05/20 11:10
	5.♥				adj simulati\$2 and design and test and	US-PGPUB;	====, 00, 20 11.10
					capacitance and parasitic adj capacitance	EPO; JPO;	
						DERWENT;	ar a
						IBM TDB	
-	-		-	4	(((703/13) or (703/14)).CCLS.) and circuit	USPĀT;	2004/05/20 11:18
		. '	•	!	adj simulati\$2 and design and test and	US-PGPUB;	
			•		capacitance and (wire interconnect) adj	EPO; JPO;	
					capacitance	DERWENT;	
_				0	ostimate2	IBM_TDB	
				υļ	estimat\$3 near2 parasitic adj capacitance	USPAT;	2004/05/20 11:19
		:		:	near8 test	US-PGPUB;	
						EPO; JPO;	
	L L		•			DERWENT;	
_				37	estimat\$3 near? namaitie ===	IBM_TDB	*
		1		J,	estimat\$3 near2 parasitic adj capacitance	USPAT;	2004/05/20 11:19
		ľ	73.		1	US-PGPUB;	
			•			EPO; JPO;	
						DERWENT;	
		_ -				IBM TDB	

Page 2

	-	1	estimat\$3 near2 parasitic adj capacitance	USPAT;	2004/05/20 11:20
		•	and test adj structure	US-PGPUB;	2331, 33, 23 11.20
				EPO; JPO;	
•				DERWENT;	
	and and a	^	Octimates many managette	IBM_TDB	
	-	- -	estimat\$3 near2 parasitic adj capacitance and test adj (device transistor capacitor)	USPAT;	2004/05/20 11:22
,		,	did test day (device transfistor capacitor)	US-PGPUB; EPO; JPO;	- (-
				DERWENT;	
	. <u>₹</u> ₹.			IBM TDB	
	-	12	Turing and the state of the sta	USPAT;	2004/05/20 14:10
			and simulation	US-PGPUB;	
	k with			EPO; JPO;	
				DËRWENT;	
	– .	2	("6243653").PN.	IBM_TDB USPAT;	2004/05/20 15:35
	. A.			US-PGPUB;	2004/05/20 15.55
				EPO; JPO;	
				DERWENT;	8
	 *	6	extraction near4 parasitic adj	IBM_TDB	
			capacitance.ti,ab,clm.	USPAT; US-PGPUB;	2004/05/20 15:36
				EPO; JPO;	
21				DERWENT;	
				IBM_TDB	
.	- ;	4	extraction near4 parasitic adj	USPAT;	2004/05/20 15:36
	*		capacitance.ti,ab,clm. and circuit near2 simulat\$3	US-PGPUB;	
			3 I Mara CV 3	EPO; JPO; DERWENT;	
				IBM TDB	
1	_ ****	0	6243653.ph. and physical\$2 near3 test\$3	USPAT;	2004/05/21 10:40
	•			US-PGPUB;	
	•			EPO; JPO;	
	.4			DERWENT;	
		0	6243653.pn. and test\$3	IBM_TDB USPAT;	2004/05/21 10:40
	•			US-PGPUB;	2004/03/21 10:40
				EPO; JPO;	
1				DERWENT;	
	_ ::.	0	(("6243653").PN.) and physical\$2 and	IBM_TDB	
		Ĭ	test\$3	USPAT; US-PGPUB;	2004/05/21 10:41
	4.			EPO; JPO;	
				DERWENT;	
			(//////////////////////////////////////	IBM_TDB	
		:	(("6243653").PN.) and test\$3	USPAT;	2004/05/21 10:41
İ				US-PGPUB;	
				EPO; JPO; DERWENT;	
Ī				IBM TDB	
	-	2	("6243653").PN.	USPAT;	2004/05/21 10:42
¥				US-PGPUB;	
-	••			EPO; JPO;	
	. *			DERWENT; IBM TDB	
	-	0	physical\$2 near2 test\$3 and extract\$3	USPAT;	2004/05/21 10:43
		·. 1	near3 parasitic adj capaciance and	US-PGPUB;	, , , , , , , , , , , , , , , , , , , ,
			simulat\$3	EPO; JPO;	
				DERWENT;	, .
	_	1 1	physical\$2 near2 test\$3 and extract\$3	IBM_TDB USPAT;	2004/05/21 10:53
	ı		near3 parasitic adj capacitance and	US-PGPUB;	2004/03/21 10:53
		,	simulat\$3	EPO; JPO;	1
				DERWENT;	
		2	("5706206").PN.	ÎBM_TDB	2004/22/23
Í		-		USPAT; US-PGPUB;	2004/05/21 11:10
				EPO; JPO;	
ļ. 			· · · · · · · · · · · · · · · · · · ·	DERWENT;	
L				IBM TDB	··
					

• :	. 1	<u></u>		•	•
	.	6	capacitance near3 test\$3 and capacitance	USPAT;	2004/05/21 11:12
•	.*		near3 design\$3 and parasitic adj	US-PGPUB;	
·			capacitance near4 test\$3 near6 design\$3	EPO; JPO;	,
٠.				DERWENT;	
		6	capacitance near3 (physical test\$3) and	IBM_TDB	10004/05/04
			capacitance near3 (simulat\$3 design\$3)	USPAT; US-PGPUB;	2004/05/21 11:13
			and parasitic adj capacitance near4 test\$3	EPO; JPO;	
	*		near6 design\$3	DERWENT;	
				IBM TDB	
	-	45	I - of the product of	USPAT;	2004/05/21 11:13
ĺ			capacitance near3 (simulat\$3 design\$3)	US-PGPUB;	
	•		and parasitic adj capacitance	EPO; JPO;	
				DERWENT;	
	_	56	(out months and anti-	IBM_TDB	
		٥٥	(extracting extraction) near4 (parasitic adj capacitance)	USPAT;	2004/05/24 19:39
		10 To 10	adj capacitance)	US-PGPUB;	
	•			EPO; JPO; DERWENT;	
				IBM TDB	
ľ	_	5	(extracting extraction) near4 (parasitic	USPAT;	2004/05/24 19:48
0			adj capacitance) and subtract\$3	US-PGPUB;	2001/09/24 19:48
				EPO; JPO;	· · · · · ·
	•			DERWENT;	*
		1		IBM_TDB	
	-	2	(extracting extraction) near4 (parasitic	USPAT;	2004/05/24 19:56
			adj capacitance) and subtract\$3 and sum	US-PGPUB;	
				EPO; JPO;	
				DERWENT;	
	_	5	(extracting extraction) near4 (parasitic	IBM TDB	2004/05/04 10 55
1			adj capacitance) and subtract\$3	USPAT; US-PGPUB;	2004/05/24 19:56
	•	;		EPO; JPO;	
ľ	,			DERWENT;	
	*			IBM TDB	
	- '	6	raphael and parasitic adj capacitance and	USPAT;	2004/05/25 14:34
			three adj dimensional	US-PGPUB;	
	· .	• .		EPO; JPO;	
.				DERWENT;	
	-	126	cmos and gate adj contact and parasitic	IBM_TDB USPAT;	2004/05/05 44 05
			adj capacitance	US-PGPUB;	2004/05/25 14:35
	• •			EPO; JPO;	
-				DÉRWENT;	ľ
				IBM TDB	
	-	. 84	width near2 gate and parasitic adj	USPAT;	2004/05/26 10:42
		; ;;;;	capacitance and (extracting extraction)	US-PGPUB;	
				EPO; JPO;	
,	*			DERWENT;	
-	<u> </u>	2	width near2 gate and parasitic adj	IBM_TDB	2004/05/05 55 ==
	•	_	capacitance near3 (extracting extraction)	USPAT;	2004/05/26 12:57
	,	\$.	(one gueeting exchaotion)	US-PGPUB; EPO; JPO;	
		ļ		DERWENT;	
		· · ·		IBM TDB	
-	•	.0	raphael.ti,ab,clm. and boundary adj	USPAT;	2004/05/26 12:57
		1	conditions	US-PGPUB;	
		<u>.</u>		EPO; JPO;	
		Ì		DERWENT;	
-		. 3	raphael and boundary adj conditions and	IBM_TDB	2004/05/05
,	Ì		parasitic adj capacitance.ti,ab,clm.	USPAT; US-PGPUB;	2004/05/26 12:57
			- J	EPO; JPO;	, '
		1		DERWENT;	. • •
		1		IBM TDB	
-		2	overlap near3 gate and parasitic adj	USPAT;	2004/05/27 13:17
		1	capacitance and raphael	US-PGPUB;	, +0.1/
		1	·	EPO; JPO;	
		,		DERWENT;	
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	<u>-</u>		3473	capacitance near3 drain near4 source	USPAT;	2004/05/27 16:40
					US-PGPUB;	
					EPO; JPO;	
					DERWENT;	
		•	100		IBM_TDB	
	·-	·	108	capacitance near3 drain near4 source and	USPAT;	2004/05/27 16:41
٠,	**	4		parasitic adj capacitance and simulation	US-PGPUB;	
1					EPO; JPO;	
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ł	• ·	٠.,	100		IBM_TDB	
			102	capacitance near3 drain near3 source and	USPAT;	2004/05/27 17:28
- 1			79	parasitic adj capacitance and simulation	US-PGPUB;	
	•		•		EPO; JPO;	
ľ					DERWENT;	
-	_		1	calibration add structure and make	IBM_TDB	
			,	calibration adj structure and parasitic	USPAT;	2004/05/27 17:29
		,·,	-	adj capacitance and test adj structure and simulation	US-PGPUB;	1.
. [, ,			Simulation	EPO; JPO;	
1		•			DERWENT;	
	- , .	. ; *	2	calibration and parasitic adj capacitance	IBM_TDB	
			· * . * . * . * . *	and test adj structure and simulation	USPAT;	2004/05/27 17:31
			:	cooc day seructure and simuration	US-PGPUB;	
			:		EPO; JPO;	
		İ			DERWENT; IBM TDB	
	<u>-</u>		.2	calibrati\$2 and parasitic adj capacitance	USPAT;	2004/05/03 13 04
	•			and test adj structure and simulation	US-PGPUB;	2004/05/27 17:31
				series and series and simulation	EPO; JPO;	
		ı			DERWENT;	
İ					IBM TDB	
	<u>.</u>		2	6449754.pn.	USPAT;	2004/05/28 09:12
	· .	•	,		US-PGPUB;	2004/03/28 09:12
.		`	ſ		EPO; JPO;	
	•		• •		DERWENT;	
					IBM TDB	* 1
1	·		19722	apparatus near3 simulating near3	USPAT;	2004/05/28 15:18
				integrated circuit near3 operation.clm.	US-PGPUB;	1 = 001,00,20 13.10
					EPO; JPO;	
		- 1			DERWENT;	f
			-		IBM_TDB	
1			0	apparatus near3 simulating near3	USPAT;	2004/05/28 15:18
				integrated adj circuit near3	US-PGPUB;	
	1		•	operation.clm.	EPO; JPO;	· ,
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	٠.			apparatus near6 simulating near6 integrated adj circuit near6	USPAT;	2004/05/28 15:22
				operation.clm.	US-PGPUB;	
1				opolacion. Cim.	EPO; JPO;	
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.	- ,		Õ	apparatus near6 simulating near6	IBM_TDB	2004/05/00 15 66
			, ,	integrated adj circuit near6	USPAT; US-PGPUB;	2004/05/28 15:23
	,			operation.ti,ab,clm.	EPO; JPO;	·
			.]		DERWENT;	
٠, .					IBM TDB	
-		ļ	1	apparatus near6 simulati\$2 near6	USPAT;	2004/05/28 15:24
				integrated adj circuit near6	US-PGPUB;	2004/03/20 15:24
				operation.ti,ab,clm.	EPO; JPÖ;	
			ļ		DERWENT;	
					IBM TDB	•
-	-].	4964	apparatus near6 simulati\$2.ti,ab,clm.	USPAT;	2004/05/28 15:24
		f			US-PGPUB;	-, - +, -0 +0 +2 +
		:		·	EPO; JPO;	
		.			DERWENT;	•
					IBM TDB	·
-			4087	apparatus near3 simulati\$2.ti,ab,clm.	USPAT;	2004/05/28 15:25
				·	US-PGPUB;	
					EPO; JPO;	*
ľ					DERWENT;	
Ŀ <u></u>			<u> </u>		IBM TDB	

383	apparatus near3 simulati\$2 near6	USPAT;	2004/05/28 15:26
	(semiconductor integrated	US-PGPUB;	*
	circuit).ti,āb,clm.	EPO; JPO;	
		DERWENT:	
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- 4	039484.ap.	USPAT;	2004/05/28 19:16
		US-PGPUB;	
1 2 4 4 4		EPO; JPO;	
		DERWENT;	1
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= 2	("6169302").PN.	USPAT;	2004/05/29 18:06
		US-PGPUB;	
		EPO; JPO;	
		DERWENT;	
	*	IBM TDB	
- 62	apparatus near3 simulating near3	USPAT;	2004/05/29 18:06
	circuit.ti,ab,clm.	US-PGPUB;	
		EPO; JPO;	
		DERWENT;	
		IBM TDB	. 1
7	apparatus near3 simulating near3	USPAT;	2004/05/29 18:07
	circuit.ti, ab, clm. and computer.ti, ab, clm.	US-PGPUB;	
	and processor ti, ab, clm. and	EPO; JPO;	
	memory.ti,ab,clm.	DERWENT;	
		IBM TDB	

Page 6